1. General description

PNP low V_{CEsat} Breakthrough In Small Signal (BISS) transistor in a leadless ultra small DFN1010D-3 (SOT1215) Surface-Mounted Device (SMD) plastic package with visible and solderable side pads.

NPN complement: PBSS4130QA.

2. Features and benefits

- Very low collector-emitter saturation voltage V_{CEsat}
- High collector current capability I_C and I_{CM}
- High collector current gain h_{FE} at high I_C
- High energy efficiency due to less heat generation
- Reduced Printed-Circuit Board (PCB) area requirements
- Solderable side pads
- AEC-Q101 qualified

3. Applications

- Loadswitch
- Battery-driven devices
- Power management
- Charging circuits
- Power switches (e.g. motors, fans)

4. Quick reference data

Table 1. Quick reference data

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|--------------------|---|---|-----|-----|------|------|
| V _{CEO} | collector-emitter voltage | open base | - | - | -30 | V |
| I _C | collector current | | - | - | -1 | Α |
| I _{CM} | peak collector current | t _p ≤ 1 ms; pulsed | - | - | -1.5 | Α |
| R _{CEsat} | collector-emitter saturation resistance | I_C = -1 A; I_B = -100 mA; pulsed; $t_p \le 300$ μs; $\delta \le 0.02$; T_{amb} = 25 °C | - | 160 | 240 | mΩ |





5. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline | Graphic symbol |
|-----|--------|-------------|---|----------------|
| 1 | В | base | | C |
| 2 | Е | emitter | | В |
| 3 | С | collector | 4 3 | '` |
| 4 | С | collector | 2 | sym132 |
| | | | Transparent top view DFN1010D-3 (SOT1215) | |

6. Ordering information

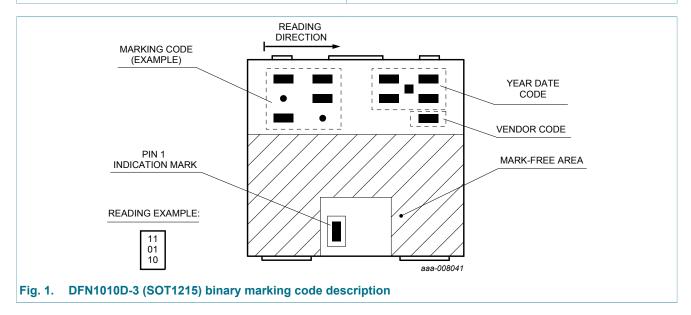
Table 3. Ordering information

| Type number | Package | kage | | | | |
|-------------|------------|--|---------|--|--|--|
| | Name | Description | Version | | | |
| PBSS5130QA | DFN1010D-3 | plastic thermal enhanced ultra thin small outline package; no leads; 3 terminals | SOT1215 | | | |

7. Marking

Table 4. Marking codes

| Type number | Marking code |
|-------------|--------------|
| PBSS5130QA | 00 10 10 |



PBSS5130QA

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8. Limiting values

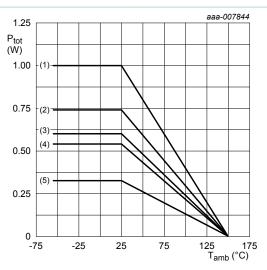
Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | | Min | Max | Unit |
|------------------|---------------------------|-------------------------------|------------|-----|------|------|
| V _{CBO} | collector-base voltage | open emitter | | - | -30 | V |
| V_{CEO} | collector-emitter voltage | open base | | - | -30 | V |
| V _{EBO} | emitter-base voltage | open collector | | - | -7 | V |
| I _C | collector current | | | - | -1 | Α |
| I _{CM} | peak collector current | t _p ≤ 1 ms; pulsed | | - | -1.5 | Α |
| I _B | base current | | | _ | -0.3 | Α |
| I _{BM} | peak base current | t _p ≤ 1 ms; pulsed | | - | -1 | Α |
| P _{tot} | total power dissipation | T _{amb} ≤ 25 °C | [1] | - | 325 | mW |
| | | | [2] | - | 600 | mW |
| | | | [3] | - | 740 | mW |
| | | | [4] | - | 540 | mW |
| | | | <u>[5]</u> | - | 1000 | mW |
| Tj | junction temperature | | | - | 150 | °C |
| T _{amb} | ambient temperature | | | -55 | 150 | °C |
| T _{stg} | storage temperature | | | -65 | 150 | °C |

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated mounting pad for collector 1 cm².
- [3] Device mounted on an FR4 PCB, single-sided copper, tin-plated mounting pad for collector 6 cm².
- [4] Device mounted on an FR4 PCB, 4-layer copper, tin-plated and standard footprint.
- [5] Device mounted on an FR4 PCB, 4-layer copper, tin-plated mounting pad for collector 1 cm².

30 V, 1 A PNP low VCEsat (BISS) transistor



- (1) FR4 PCB, 4-layer copper, 1 cm²
- (2) FR4 PCB, single-sided copper, 6 cm²
- (3) FR4 PCB, single-sided copper, 1 cm²
- (4) FR4 PCB, 4-layer copper, standard footprint
- (5) FR4 PCB, single-sided copper, standard footprint

Fig. 2. Power derating curves

9. Thermal characteristics

Table 6. Thermal characteristics

| Symbol | Parameter | Conditions | | Min | Тур | Max | Unit |
|--------------------------|--------------------|-------------|------------|-----|-----|-----|------|
| R _{th(j-a)} | thermal resistance | in free air | [1] | - | - | 385 | K/W |
| from junction to ambient | | [2] | - | - | 209 | K/W | |
| | ambient | | [3] | - | - | 169 | K/W |
| | | | [4] | - | - | 232 | K/W |
| | | | <u>[5]</u> | - | - | 125 | K/W |

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated mounting pad for collector 1 cm².
- [3] Device mounted on an FR4 PCB, single-sided copper, tin-plated mounting pad for collector 6 cm².
- [4] Device mounted on an FR4 PCB, 4-layer copper, tin-plated and standard footprint.
- [5] Device mounted on an FR4 PCB, 4-layer copper, tin-plated mounting pad for collector 1 cm².

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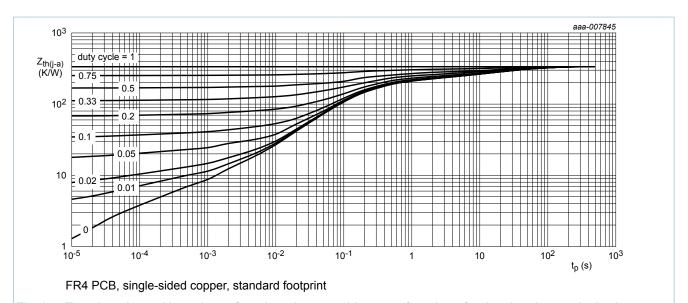


Fig. 3. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

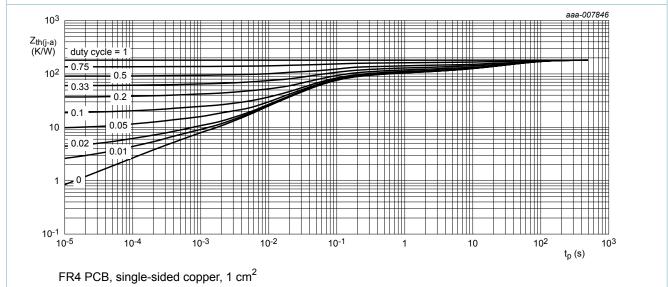


Fig. 4. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

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30 V, 1 A PNP low VCEsat (BISS) transistor

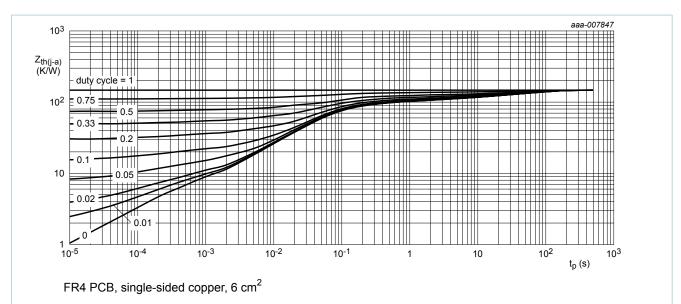


Fig. 5. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

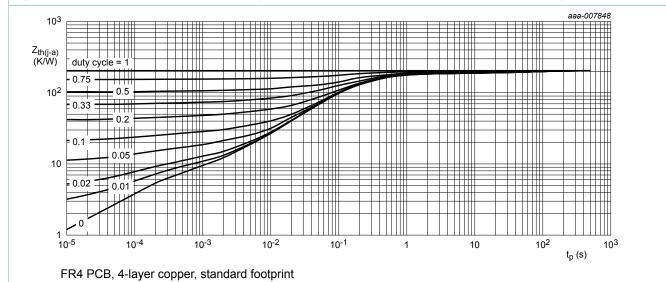
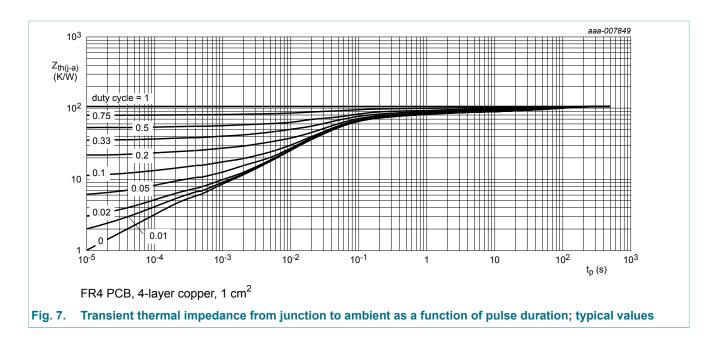


Fig. 6. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

30 V, 1 A PNP low VCEsat (BISS) transistor



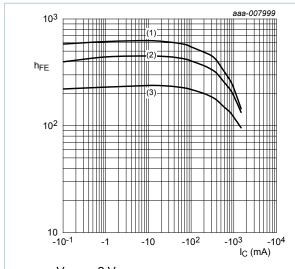
10. Characteristics

Table 7. Characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|--------------------|---|--|-----|------|------|------|
| I _{CBO} | collector-base cut-off | V _{CB} = -24 V; I _E = 0 A; T _{amb} = 25 °C | - | - | -100 | nA |
| current | current | V _{CB} = -24 V; I _E = 0 A; T _j = 150 °C | - | - | -50 | μA |
| I _{CES} | collector-emitter cut-off current | V _{CE} = -24 V; V _{BE} = 0 V; T _{amb} = 25 °C | - | - | -100 | nA |
| I _{EBO} | emitter-base cut-off current | $V_{EB} = -5 \text{ V}; I_{C} = 0 \text{ A}; T_{amb} = 25 \text{ °C}$ | - | - | -100 | nA |
| h _{FE} | DC current gain | V_{CE} = -2 V; I_{C} = -100 mA; t_{p} ≤ 300 μs; δ ≤ 0.02 ; T_{amb} = 25 °C; pulsed | 250 | 425 | - | |
| | | V_{CE} = -2 V; I_{C} = -500 mA; t_{p} ≤ 300 μs; δ ≤ 0.02 ; T_{amb} = 25 °C; pulsed | 180 | 295 | - | |
| | | V_{CE} = -2 V; I_{C} = -1 A; t_{p} ≤ 300 µs; δ ≤ 0.02 ; T_{amb} = 25 °C; pulsed | 130 | 200 | - | |
| V _{CEsat} | collector-emitter saturation voltage | I_{C} = -500 mA; I_{B} = -50 mA; t_{p} ≤ 300 µs; δ ≤ 0.02 ; T_{amb} = 25 °C | - | -85 | -130 | mV |
| | | I_C = -1 A; I_B = -50 mA; t_p ≤ 300 μs; δ ≤ 0.02 ; T_{amb} = 25 °C | - | -180 | -260 | mV |
| | | I_{C} = -1 A; I_{B} = -100 mA; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; \ T_{amb}$ = 25 °C | - | -160 | -240 | mV |
| R _{CEsat} | collector-emitter saturation resistance | I_C = -1 A; I_B = -100 mA; pulsed; t_p ≤ 300 μs; δ ≤ 0.02; T_{amb} = 25 °C | - | 160 | 240 | mΩ |

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| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|--|---------------------------------|---|-----|-------|-------|------|
| V _{BEsat} base-emitte voltage | base-emitter saturation voltage | I_C = -500 mA; I_B = -50 mA; pulsed; $t_p \le 300 \ \mu s; \ \delta \le 0.02 \ ; T_{amb}$ = 25 °C | - | -0.88 | -1 | V |
| | | I_{C} = -1 A; I_{B} = -50 mA; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; T_{amb}$ = 25 °C | - | -0.93 | -1.05 | V |
| | | I_{C} = -1 A; I_{B} = -100 mA; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; \ T_{amb}$ = 25 °C | - | -0.96 | -1.1 | V |
| V_{BEon} | base-emitter turn-on voltage | V_{CE} = -2 V; I_{C} = -0.5 A; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; T_{amb}$ = 25 °C | - | -0.78 | -0.9 | V |
| t _d | delay time | V _{CC} = -10 V; I _C = -0.5 A; I _{Bon} = -25 mA; I _{Boff} = 25 mA; T _{amb} = 25 °C | - | 10 | - | ns |
| t _r | rise time | | - | 30 | - | ns |
| t _{on} | turn-on time | | - | 40 | - | ns |
| t _s | storage time | _ | - | 270 | - | ns |
| t _f | fall time | | - | 45 | - | ns |
| t _{off} | turn-off time | | - | 315 | - | ns |
| f⊤ | transition frequency | V_{CE} = -10 V; I_{C} = -50 mA; f = 100 MHz; T_{amb} = 25 °C | 120 | 170 | - | MHz |
| C _c | collector capacitance | $V_{CB} = -10 \text{ V}; I_E = 0 \text{ A}; i_e = 0 \text{ A};$ $f = 1 \text{ MHz}; T_{amb} = 25 ^{\circ}\text{C}$ | - | 14 | 16 | pF |



 $V_{CE} = -2 V$

(1) $T_{amb} = 100 \, ^{\circ}C$

(2) $T_{amb} = 25 \, ^{\circ}C$

(3) $T_{amb} = -55 \, ^{\circ}C$

Fig. 8. DC current gain as a function of collector current; typical values

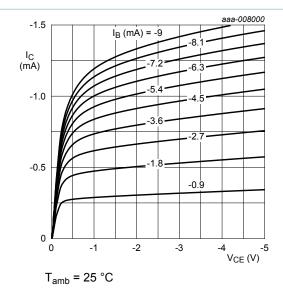
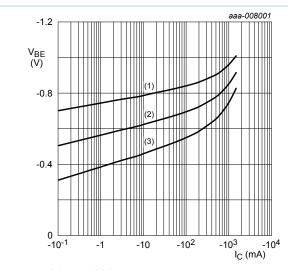


Fig. 9. Collector current as a function of collectoremitter voltage; typical values

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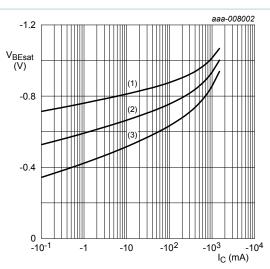
$$V_{CE} = -2 V$$

(1)
$$T_{amb} = -55 \, ^{\circ}C$$

(2)
$$T_{amb}$$
 = 25 °C

(3)
$$T_{amb}$$
 = 100 °C

Fig. 10. Base-emitter voltage as a function of collector current; typical values



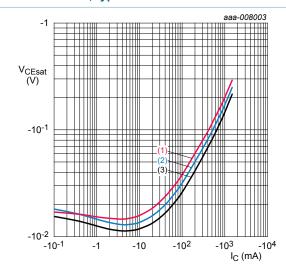
$$I_{\rm C}/I_{\rm B} = 20$$

(1)
$$T_{amb} = -55 \, ^{\circ}C$$

(2)
$$T_{amb} = 25 \, ^{\circ}C$$

(3)
$$T_{amb} = 100 \, ^{\circ}C$$

Fig. 11. Base-emitter saturation voltage as a function of collector current; typical values



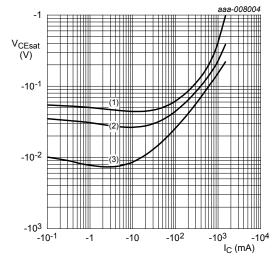
$$I_{\rm C}/I_{\rm B} = 20$$

(1)
$$T_{amb} = 100 \, ^{\circ}C$$

(2)
$$T_{amb}$$
 = 25 °C

(3)
$$T_{amb} = -55 \, ^{\circ}C$$

Fig. 12. Collector-emitter saturation voltage as a function of collector current; typical values



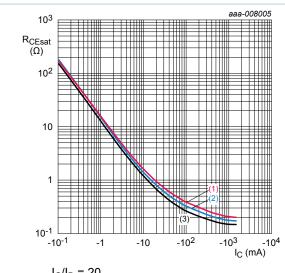
(1)
$$I_C/I_B = 100$$

(2)
$$I_C/I_B = 50$$

(3)
$$I_C/I_B = 10$$

Fig. 13. Collector-emitter saturation voltage as a function of collector current; typical values

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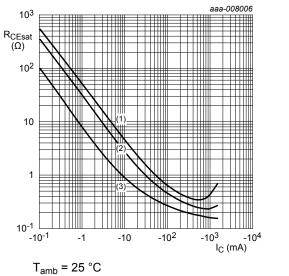
$$I_{\rm C}/I_{\rm B} = 20$$

(1)
$$T_{amb} = 100 \, ^{\circ}C$$

(2)
$$T_{amb}$$
 = 25 °C

(3)
$$T_{amb} = -55 \, ^{\circ}C$$

Fig. 14. Collector-emitter saturation resistance as a function of collector current; typical values



(1)
$$I_C/I_B = 100$$

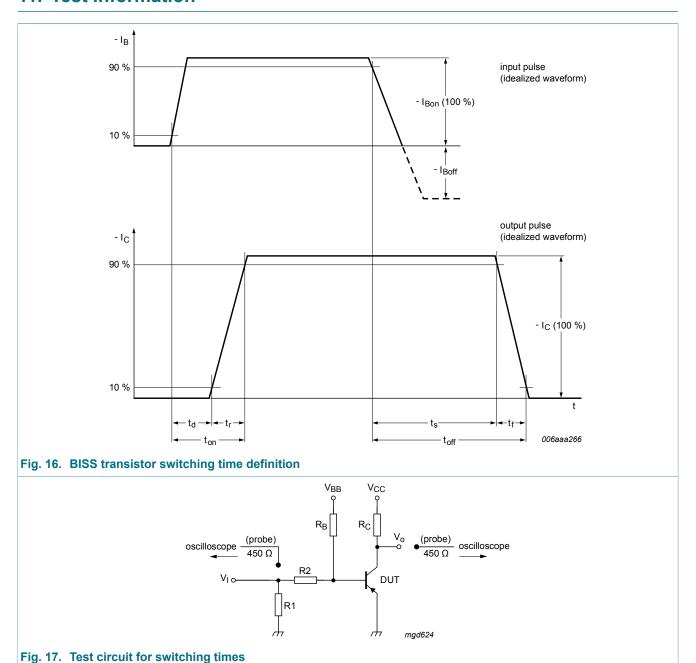
(2)
$$I_C/I_B = 50$$

(3)
$$I_C/I_B = 10$$

Fig. 15. Collector-emitter saturation resistance as a function of collector current; typical values

30 V, 1 A PNP low VCEsat (BISS) transistor

11. Test information

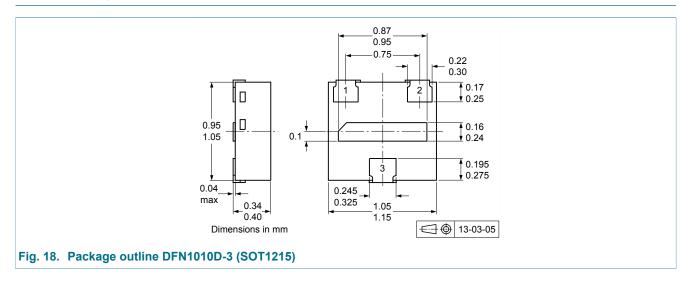


11.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard *Q101 - Stress test qualification for discrete semiconductors*, and is suitable for use in automotive applications.

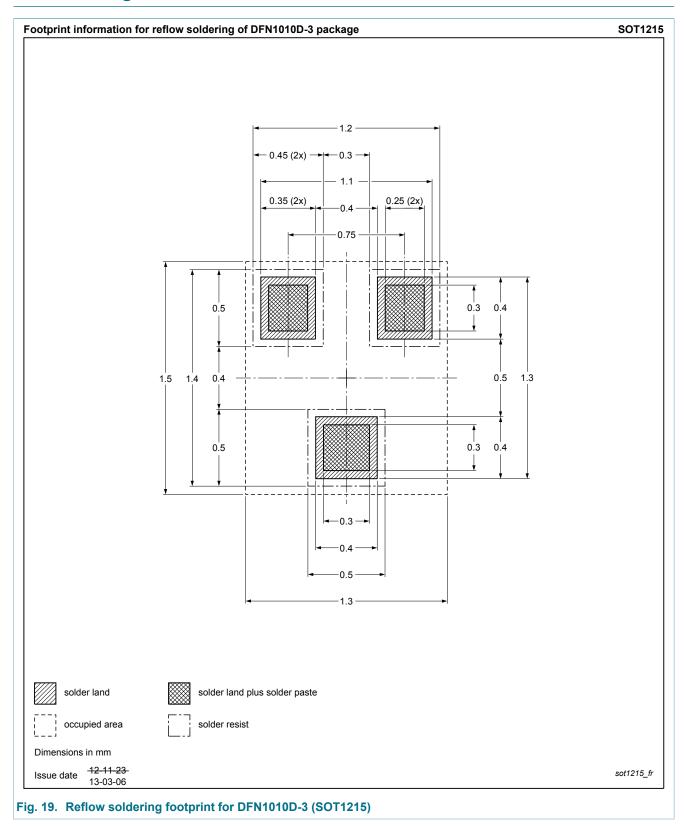
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12. Package outline



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13. Soldering



PBSS5130QA

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14. Revision history

Table 8. Revision history

| Data sheet ID | Release date | Data sheet status | Change notice | Supersedes |
|----------------|--------------|--------------------|---------------|------------|
| PBSS5130QA v.1 | 20130828 | Product data sheet | - | - |

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15. Legal information

15.1 Data sheet status

| Document status [1][2] | Product status [3] | Definition |
|--------------------------------------|--------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
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